

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of
Tsuyoshi KANEKO et al.

Application No.: 10/649,891

Filed: August 28, 2003

For: OPTICAL COMPONENT AND MANUFACTURING METHOD THEREOF,
MICROLENS SUBSTRATE AND MANUFACTURING METHOD THEREOF, DISPLAY
DEVICE, AND IMAGING DEVICE



Group Art Unit: 2812

Examiner: A. STEVENSON

Docket No.: 116565

INFORMATION DISCLOSURE STATEMENT

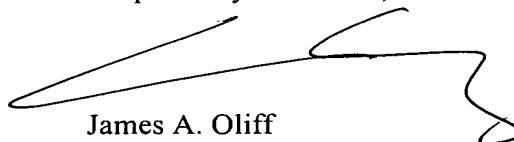
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed before the mailing date of a first Office Action on the merits after the filing of a Request for Continued Examination under 37 CFR §1.114. No certification or fee is required.
- ☒ 2. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.

Respectfully submitted,



James A. Oliff
Registration No. 27,075

Gang Luo
Registration No. 50,559

JAO:GL/smo

Date: February 21, 2006

OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
Telephone: (703) 836-6400

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Sheet 1 of 1

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 116565		APPLICATION NO. 10/649,891	
				APPLICANT(S) Tsuyoshi KANEKO et al.			
				FILING DATE August 28, 2003		GROUP 2812	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)							
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
	1.	5,229,016	7/20/1993	Hayes et al.			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER					DATE CONSIDERED		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: February 21, 2006